Search Notes

Application/Control N	c
10/679,000	
Examiner	_

Applicant(s)/Patent under Reexamination	, ,
CHANG ET AL.	
Art Unit	

Sheng-Jen	Tsa

Reexamination	
CHANG ET AL.	
Art Unit	
2186	

SEARCHED			
Class	Subclass	Date	Examiner
714	763	10/10/2006	SJT
711	103	10/10/2006	SJT
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East: "ECC" with "flash" "NAND flash memoy" "MLC NAND flash memory" "hamming code"	10/10/2006	SJT